Table-Top EUV/Soft X-ray Source



A laser-based plasma source for generation of EUV/soft x-ray radiation was developed at the Laser-Laboratorium Göttingen. The plasma is produced by an Nd:YAG laser (1064nm, 800mJ, 7ns) that is focused into a pulsed gas jet. Different target gases can be used for the generation of either intense broad-band (XUV: Krypton, Argon, EUV: Xenon) or less intense narrow-band radiation (XUV: Nitrogen, EUV: Oxygen), respectively.

Specifications

Wavelength 1...20 nm

Pulse duration 7 ns

Pulse energy (Xe)3.5 mJ

 $(4\pi \text{ sr}, 2\% \text{ BW})$

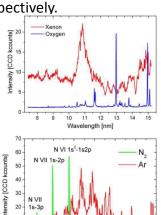
Conversion eff. (Xe) 0.45 %

Plasma shape Ø ~ 300 μm

Repetition rate up to 10 Hz

Nd:YAG Laser

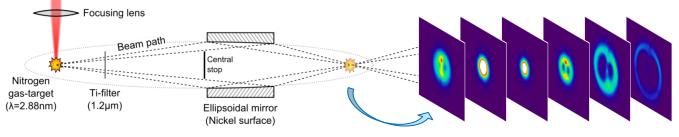
800mJ, 7ns





▲ Emission spectra of various target gases

Sketch of the source equipped with an ellipsoidal focusing mirror. Intensity profiles indicate the beam shape measured behind the optic.



Advantages

- Low debris
- High EUV energy (3.5 mJ)
- Minimum gas consumption (duration of gas pulse: < 1 ms)</p>
- Simple target gas exchange
- Table-top system

Applications

- Metrology: Reflectometry, absorption spectroscopy (NEXAFS)
- Optics/sensor testing
- EUV damage investigations
- Fundamental studies on material interaction
- Water window microscopy (λ = 2 .. 4 nm)

Aunion Tech Co.,Ltd

Floor 3, F Building, No. 86 Caobao road, Shanghai 200235 P.R. China Tel: +86-21-51083793 Fax:+86-21-34241962

E-Mail: info@auniontech.com Website: www.auniontech.com